Draft
Minutes
ASC OP/TF 2, Performance Based Optical Imperfections Task Force Draft Standard Meeting
May 11, 2009, 8:30 a.m. – 12 Noon
Rochester Convention Center, Aqueduct Room
123 Main St E
Rochester, NY 14604

☒**Committee Members (13 of 20 w/2 alt.)**	Representing
☒David Aikens (by phone)	Savvy Optics Corporation
☒Gordon Boultbee	JDSU Corporation
☐Andrei Brunfeld	Xyrtex
☐Benjamin Catching (Alternate)	JDSU Corporation
☐David Corridon	Individual
☒Walter Czajkowski	APOMA (Edmund Optics)
☐Jesica DeGroote Nelson	Optimax Systems, Inc.
☒Frank Dombrowski	Gage-Line Technology, Inc.
☒Marla Dowell	IEEE/LEOS (NIST)
☒Marla Dowell	NIST
☐Lincoln Endelman	SPIE, (Endelman Enterprises)
☒Charles Gaugh	Davidson Optronics, Inc.
☐Ulf Griesmann	OSA (NIST)
☐Krishna Gupta	Zygo Corporation
☐Hal Johnson	Harold Johnson Optical Lab
☒Donna Howland	Northrop Grumman Aerospace Systems
☒Alan Krisiloff	Triptar Lens Co., Inc.
☐Jonathan McGuire	Northrop Grumman Laser Systems
☒Ashish Mistry	FLIR Precision Optics
☒Rick Plympton (Alternate)	Optimax Systems, Inc.
☐Sam Richman (Alternate)	Research Electro-Optics, Inc.
☐William Royall	Eastman Kodak Company, Retired
☒Trey Turner	Research Electro-Optics, Inc.
☒Ray Williamson	Ray Williamson Consulting
Observers (4)	
☒Gene Kohlenberg	OEOSC
☒Iris Erichsen	Trioptics GmbH
☐Ari Siletz	CCDMETRIX

1. Welcome and Introductions

G. Boultbee opened the meeting at 8:38 a.m. He named each person in the room and on the phone.

2. Adoption of Agenda

G. Boultbee asked for a motion to approve the draft agenda. D. Aikens asked to discuss POG's development of reference standards. R. Plympton made the motion to accept the amended agenda, and M. Dowell seconded it. The motion carried unanimously.

3. Approval of the Monday, January 25, 2009 ASC OP/SC 1, BSR/OEOSC-OP1.002, Optics and Electro-Optical Instruments – Optical Elements and Assemblies — Appearance Imperfections Draft Review Minutes

A. Krisiloff moved that the minutes be accepted and W. Czajkowski seconded the motion. The motion carried unanimously.

4. Status of Release of ANSI/OEOSC OP1.002-2009 (Rev 2006)

D. Aikens reported that he was able to put a press release in the New York Photonics Rochester Cluster newsletter concerning release of OP1.002. D. Aikens will give Secretary link to put on the OEOSC news page.

5. **Report on visit by OEOSC representatives to Picatinny Arsenal in NJ (verbal supplement to trip report already published)**

D. Aikens distributed minutes of the meeting. W. Royall agreed to draft a letter for Picatinny; he has submitted it to D. Aikens for review.

D. Aikens will send out a strategy document outlining the objectives for requesting changes to MIL-O-13830 to the committee to clarify the visibility standard, and to clarify how the evaluations are done and the accumulations are performed.

D. Aikens will distribute W. Royall's draft letter for Picatinny to committee members for review.

6. **Update on development of scratch inspection vision system being developed by Savvy Optics and Ari Siletz**

D. Aikens made the presentation by phone while those attending the meeting viewed his prepared slides.

Instruments are going out for beta testings. He expected to begin shipping units in July.

The Task Force recessed at 9:58 a.m. and reconvened at 10:12 a.m.

7. **Update of POG Standards**

F. Dombrowski suggested that a scale be included on the Annex B artifact. He asked if a manufacturer could put its name on the artifact. G. Boultbee said that it could be.

8. **Review and discussion of inputs on New Work Item for Rev. 3 of OP1.002**

A. Krisiloff discussed the project. He was under the impression that binning is a good concept. W. Royall called binning discrete, and a system where a specification calls a particular number in the whole range is a continuous specification. G. Boultbee's issue was how the item 3.5.5.2 was written, not with the concept in general. The standard should say that if a need falls within a bin, then the user must go to the next smaller bin.

It was agreed that binning is the preferred way to specify imperfections. There should not be a notation for continuous specification.

3.5.3 A. Krisiloff discussed the condition when specifications are listed as exclusive or inclusive specifically with regard to accumulation. Accumulation is performed by a quality engineer rather than someone doing the inspection.

It is acceptable to ignore imperfections below some limit. On a shop floor, language is exclusionary while in the lab the language is inclusionary.

In **Table 2, Dig Designation**, column two should be called Dig Diameter rather than Average Dig Diameter.

It was suggested that the second sentence in **3.5.3** be dropped.

D. Aikens did not like the new language in **3.6.1** and **3.6.2**. He and A. Krisiloff to discuss it after the meeting.

T. Turner's microscope inspection. A. Mistry suggested that a loupe should also be included. M. Dowell suggested that this be an informative annex.

D. Aikens said that there is a need for high level illumination testing. An included example could help those who are working in this area.

Sleeks: D. Aikens said that he wanted to have a statement saying whether sleeks count as an imperfection. A. Krisiloff asked Plympton and Turner to give him their definition of sleeks. D. Aikens said he would provide the ISO definition.

9. **Status of One-Hour Overview Presentation on the various scratch and dig standards**

There was no time to cover this topic.

10. **Time and Place of next TF 2 Meeting**

Nine of those attending preferred to meet in San Diego in August, one preferred to meet in San Jose in October.

11. **Adjourn**

M. Dowell moved that the meeting be adjourned; A. Krisiloff seconded the motion, which carried unanimously. The meeting adjourned at 12:05 p.m.